

OMEGA TYPE ICT-006 is a completely self contained programmable IC Tester, designed to stringently test the IC's under actual operating conditions before it is actually put in the circuit.

The IC Tester can test all types of TTL (74 & 54 series) and CMOS logic gates IC's like AND, OR, NOT, BUFFERS, NAND, NOR other IC's like FLIP-FLOPS, MULTIVIBRATORS, LATCHES, MEMORIES, STORAGE REGISTERS, SHIFT REGISTERS, COUNTERS, DECODERS, ENCODERS, MULTIPLEXERS, DEMULTIPLEXERS, FULL ADDERS, HALF ADDERS, PARITY GENERATORS/SYNCHRONIZERS etc.

SPECIFICATIONS

01 IC BASE:

A 16 Pin gold plated Zero Insertion Force (ZIF) dual in line Package (DIP) on Front Panel.

02 MATRIX PROGRAMMER:

Uses 16 number of 10 position Thumb Wheel Switches (TWS)

03 THUMB WHEEL SWITCHES:

Sixteen Pin gold plated I.C. base is provided, each pin of which can be connected to the following ten positions through sixteen thumb wheel switches (TWS). 0 'LO' level, 1 'HI' level,2 Vcc,3 Display, 4 Positive pulse, 5 Negative pulse, 6 Clock, 7 Interconnected, 8 Ground, 9 No connection

- 3.1 'LO' Level : (Low Level - logic zero) 'LO' level can be adjusted from '0' volt to '2' volt continuously.
- 3.2 'HI' Level : (High Level - logic one) 'HI' level can be adjusted

from 1 volt to 4.5 volt continuously.

3.3 Vcc:

Supply voltage can be varied from 4.5 to 5.5 volts. Another supply of 5 volt is also available externally which can be loaded upto 1 Amp. This power supply is short circuit protected with fold back current limiting.

3.4 Display:

All the pins of the I.C. under test are monitored. Each pin has a corresponding LED (total 16 LEDs) for displaying the state of the pin.

3.5 Positive and Negative pulse :

A manual push button is used to generate positive and negative going pulse. The pulse is generated when push button is in the depressed position. The positive and negative pulse are available simultaneously at the output and has a fan out capability of about10 U.L.

3.6 Clock:

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An uncelebrated clock is provided whose frequency can be varied using a three position range selector and fine frequency control. The

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frequency of the clock can be varied approximately from 1Hz to 1 KHz. The clock is also available externally with a fanout capability of about 10 U.L.

3.7 Inter Connect:

Facility for interconnecting any pins of the I.C. under test. All the pins whose corresponding thumbwheel switches are kept in 'INTERCONNECT' position (i.e. 7th position) are shorted.

3.8 No connection:

This position leaves the pin open without connecting it to any other position.

04 METERING:

One meter is provided on the front panel which can be selected through band switch to monitor the following : 4.1 Vcc.

- 4.1 vcc, 4.2 'HI' level
- 4.2 Hi level 4.3 'LO' level
 - .3 LU level
- 4.4 Current taken by the I.C. under test

(NOTE: This will not indicate the current taken by the external load, if any, and will always show the current taken by the I.C. under test).

05 MISCELLANEOUS:

- 5.1 Sixteen sockets are provided at the right hand side wall of the unit, these correspond to 16 pins of the IC under test.
- 5.2 Sixteen, Two positioned toggle switches, corresponding to each TWS provided, with NORMAL and OPEN COLLECTOR marking. When these switches are kept on OPEN COLLECTOR position, testing of OPEN COLLECTOR IC's can be done without any extra arrangement.

06 POWER REQUIREMENT:

230V ±10% at 50 Hz AC. Mains

- 07 Weight : 8 Kg. (Approx)
- 08 Dimension : $W415 \times H165 \times D315$
- 09 Strongly supported by detailed Operating Instructions.

We are committed to the continuous development of our products, and therefore reserve the right to amend specifications without prior notice

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